

Search Notes**Application/Control No.**

10/695,375

Examiner

Chau Nguyen

Applicant(s)/Patent under Reexamination

BEZRUKOV ET AL.

Art Unit

2176

SEARCHED

Class	Subclass	Date	Examiner
715	513	2/2/2006	CN
715	530	2/2/2006	CN
707	102	2/2/2006	CN
707	103R	2/2/2006	CN
707	103Y	2/2/2006	CN
707	103Z	2/2/2006	CN
707	200	2/2/2006	CN

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East Reports	2/2/2006	CN
	2/3/2006	CN
NPL Search on IEEE Database	2/3/2006	CN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner